

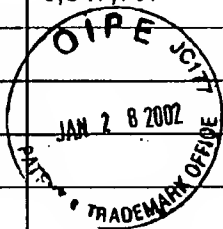
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Sheet 1 of 2

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1773	APPLICATION NO. 09/995,781
LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)		FIRST NAMED INVENTOR Yukihiro ABIKO et al.	
		FILING DATE November 29, 2001	GROUP ART UNIT 2614

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
OK	AA	5,847,767	12/8/98	Ueda	348	423	9/2/97
	AB						
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	AD						
	AE						
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### FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
OK	AG	JP-A-10-23421	1/23/98	Japan			Abst	
OK	AH	JP-A-6-153146	5/31/94	Japan			Abst	
OK	AI	JP-A-6-54315	2/25/94	Japan			Abst	
OK	AJ	JP-A-11-8854	1/12/99	Japan			X	
OK	AK	JP-A-2-174387	7/5/90	Japan			Abst	
OK	AL	JP-A-4-10788	1/14/92	Japan			Abst	

### OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

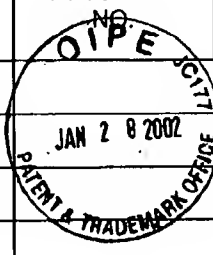
OK	AM	Y. Niikura et al., "Scene Change Detection from MPGE Coded Data", IEEJ, CMN-97-37~43, September 25, 1997, pp. 7-12.
OK	AN	S. Yamada et al., "A Scene-Change Detection Method For The Video Including The Special Effects", ITE, April 21, 1994, pp. 21-26.

EXAMINER  	DATE CONSIDERED  10/27/2004
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
<i>al</i>	AG	JP-A-9-214975	8/15/97	Japan			Abst	
	AH							
	AI							
	AJ							
	AK							
	AL							

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER  <i>[Signature]</i>	DATE CONSIDERED  10/27/2004
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